

Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

230257US0

SERIAL NO.

10/664,894

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Nathalie JAGER-LEZER

FILING DATE

September 22, 2003

GROUP

1619

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
J.V.	AA	2002/098217	07/25/2002	B. Piot, et al.			
	AB	2003/0031642	02/13/2003	N. Jager Lezer			
	AC	2004/0142831	07/22/2004	N. Jager Lezer			
	AD	2006/057085	03/16/2006	N. Jager Lezer			
	AE	3,802,841	04/09/1974	Jean-Baptiste Robin			
	AF	5,324,506	06/28/1994	L. Calvo, et al.			
	AG	6,491,931	12/10/2002	N. Collin			
	AH	6,503,521	01/07/2003	B. Atis, et al.			
	AI	6,955,805	10/18/2005	A. Shah, et al.			
	AJ						
	AK						
	AL						
	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
	AO	EP 1 201 221	05/02/2002	EPO (Corresponds to US 2002/098217)		X
	AP	EP 1 053 742	11/22/2000	EPO (Corresponds to US 2006/057085) (English Abstract Provided)		X
	AQ	EP 1 208 836	05/29/2002	EPO	X	
	AR	EP 0 445 342	09/11/1991	EPO	X	
	AS	WO 00/72809	12/07/2000	WIPO	X	
	AT	JP H09-263 518	10/07/1997	Japan (English Abstract Provided)		X
	AU	JP 2002-154932	05/28/2002	Japan (English Abstract Provided)		X
	AV	JP 2001-48736	02/20/2001	Japan (English Abstract Provided)		X

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
	AX	
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

/Jyothisna Venkat/

Date Considered

05/25/2009

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 230257US0		SERIAL NO. 10/664,894	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Nathalie JAGER-LEZER			
				FILING DATE September 22, 2003		GROUP 1619	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
J.V.V.	AO	JP 2001-48750	02/20/2001	Japan (English Abstract Provided)		X	
↓	AP	JP 2002-145739	05/22/2002	Japan (Corresponds to US 2002/098217) (English Abstract Provided)		X	
	AQ	JP 2000-344627	12/12/2000	Japan (English Abstract Provided)		X	
	AR	JP 2002-173412	06/21/2002	Japan (Corresponds to US 6,503,521)		X	
	AS	JP 2004-155768	06/03/2004	Japan (w/English Translation)	X		
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Jyothsna Venkat/				Date Considered 05/25/2009			
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							